UNITED STATES DEPARTMENT OF COMMERCE United States Patent and Trademark Office Address: COMMISSIONER FOR PATENTS P.O. Box 1450 Alexandria, Virginia 22313-1450 www.uspto.gov

APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.
10/588,708	08/09/2006	Toshiaki Sasaki	81844.0052	2456
	7590 09/24/200 ARTSON L.L.P.	EXAMINER		
1999 AVENUE	E OF THE STARS	GARDNER, SHANNON M		
SUITE 1400 LOS ANGELE	S, CA 90067	ART UNIT	PAPER NUMBER	
			1795	
			NOTIFICATION DATE	DELIVERY MODE
			09/24/2009	ELECTRONIC

## Please find below and/or attached an Office communication concerning this application or proceeding.

The time period for reply, if any, is set in the attached communication.

Notice of the Office communication was sent electronically on above-indicated "Notification Date" to the following e-mail address(es):

ctkeyner@hhlaw.com LAUSPTO@hhlaw.com lbrivero@hhlaw.com

## Advisory Action Before the Filing of an Appeal Brief

Application No.	Applicant(s)		
10/588,708	SASAKI ET AL.		
Examiner	Art Unit		
Shannon Gardner	1795		

Sh	annon Gardner	1795	
The MAILING DATE of this communication appears	on the cover sheet with the	correspondence add	ress
THE REPLY FILED 20 August 2009 FAILS TO PLACE THIS APPL	CATION IN CONDITION FOR	ALLOWANCE.	
1. The reply was filed after a final rejection, but prior to or on the application, applicant must timely file one of the following repli application in condition for allowance; (2) a Notice of Appeal (for Continued Examination (RCE) in compliance with 37 CFR periods:	same day as filing a Notice of es: (1) an amendment, affidavi with appeal fee) in compliance	Appeal. To avoid abar it, or other evidence, w with 37 CFR 41.31; or	hich places the (3) a Request
a) The period for reply expiresmonths from the mailing date b) The period for reply expires on: (1) the mailing date of this Advisor no event, however, will the statutory period for reply expire later to Examiner Note: If box 1 is checked, check either box (a) or (b). Of MONTHS OF THE FINAL REJECTION. See MPEP 706.07(f).	ory Action, or (2) the date set forth han SIX MONTHS from the mailin	g date of the final rejectio	n.
Extensions of time may be obtained under 37 CFR 1.136(a). The date on w have been filed is the date for purposes of determining the period of extension under 37 CFR 1.17(a) is calculated from: (1) the expiration date of the shorteset forth in (b) above, if checked. Any reply received by the Office later than may reduce any earned patent term adjustment. See 37 CFR 1.704(b). NOTICE OF APPEAL	on and the corresponding amount ened statutory period for reply origi	of the fee. The appropria inally set in the final Offic	ate extension fee e action; or (2) as
2. The Notice of Appeal was filed on A brief in compliant filing the Notice of Appeal (37 CFR 41.37(a)), or any extension Notice of Appeal has been filed, any reply must be filed within AMENDMENTS	n thereof (37 CFR 41.37(e)), to	avoid dismissal of the	
3. The proposed amendment(s) filed after a final rejection, but p  (a) They raise new issues that would require further conside  (b) They raise the issue of new matter (see NOTE below);  (c) They are not deemed to place the application in better for appeal; and/or  (d) They present additional claims without canceling a corre	eration and/or search (see NO	TE below); ducing or simplifying th	
NOTE: (See 37 CFR 1.116 and 41.33(a)).  4.  The amendments are not in compliance with 37 CFR 1.121. §  5.  Applicant's reply has overcome the following rejection(s):  6.  Newly proposed or amended claim(s) would be allowan non-allowable claim(s).	See attached Notice of Non-Co	mpliant Amendment (I	
7. For purposes of appeal, the proposed amendment(s): a) whow the new or amended claims would be rejected is provided. The status of the claim(s) is (or will be) as follows:  Claim(s) allowed:  Claim(s) objected to:  Claim(s) rejected: 1-3, 5-7, 9-11.  Claim(s) withdrawn from consideration:		ll be entered and an ex	planation of
AFFIDAVIT OR OTHER EVIDENCE			
<ol> <li>The affidavit or other evidence filed after a final action, but bet because applicant failed to provide a showing of good and suf was not earlier presented. See 37 CFR 1.116(e).</li> </ol>	ficient reasons why the affidav	it or other evidence is	necessary and
9. The affidavit or other evidence filed after the date of filing a Not entered because the affidavit or other evidence failed to overdeshowing a good and sufficient reasons why it is necessary and	ome <u>all</u> rejections under appea	al and/or appellant fails	s to provide a
10. ☐ The affidavit or other evidence is entered. An explanation of REQUEST FOR RECONSIDERATION/OTHER  11. ☑ The request for reconsideration has been considered but doe		·	
see Continuation Sheet.  12. Note the attached Information Disclosure Statement(s). (PTC 13. Other:			
/Jennifer K. Michener/ Supervisory Patent Examiner, Art Unit 1795	/S. G./ Examiner, Art Unit 1795		

Continuation of 11. does NOT place the application in condition for allowance because:

Applicant has amended claim 1 to include the limitations from the previously listed claim 8, which is now cancelled.

The Examiner notes that claim 1 is still unpatentable over Tawada in view of Matsui and Robinson. Tawada in view of Matsui teach the limitations of claim 1 but are silent as to the transparent micro-particles having an average particle diameter of not less than 10 nm and not more than 95 nm. However, it is known in the art to create a substrate containing silica micro-particles (such as those used in modified Tawada) with particles having an average diameter of 5 to 25 nm, thus creating an improved flexible substrate surface with good high-temperature dimensional stability and high optical clarity, as taught by Robinson (paragraphs [0012]-[0018] and [0025]). Therefore, it would have been obvious to one of ordinary skill in the art at the time of the invention to utilize silica micro-particles having an average diameter of 5 to 25 nm in the invention of modified Tawada to create an improved substrate surface as taught by Robinson.

The Examiner further notes that in the case where the claimed ranges 'overlap or lie inside ranges disclosed by the prior art' a prima facie case of obviousness exists. Further still, the teachings of Tawada provide for micro-particles of 0.1 to 1.0 microns (100nm to 1000nm). A prima facie case of obviousness exists where the claimed ranges and prior art ranges do not overlap but are close enough that one skilled in the art would have expected them to have the same properties (see MPEP 2144.05).

Claims 2-3, 5-7 and 9-11 stand rejected as previously presented in the Office Action dated 6/22/2009.

Applicant argues that "the Office has failed to present an adequate showing as to why Tawada's teaching of an average diameter of 0.1 to 1.0 microns should be ignored in favor of Robinson's teaching of an average diameter of 5 to 25 nm" (pp 7 of Arguments).

The Examiner directs Applicant to the final Office Action of 6/22/2009 for a full discussion of the references. Tawada teaches a general range for the average diameter of his mirco-particles. However, one of ordinary skill in the art at the time of the invention would have looked to the teachings of the prior art for ways to further develop the substrate containing the micro-particles. Particularly, one of ordinary skill would have looked to the teachings of Robinson for information on improvements to the substrate by utilizing micro-particles sized 5 nm to 25 nm.

Applicant argues that "The surfaces disclosed in Matsui are different than the surfaces of the present invention...Matsui teaches the uneveness of the ZnO layer but is silent as to the uneveness of the transparent foundation layer" (pp 8 of Arguments).

The Examiner notes that Matsui is relied upon as a general teaching regarding the use of textured substrates with a RMS roughness of a specified value to improve the conversion efficiency (see abstract and Introduction). It would have been obvious to one of ordinary skill in the art at the time of the invention to apply this teaching to the transparent insulating substrate of Tawada to improve the conversion efficiency.